

# FMV17N60ES

#### **FUJI POWER MOSFET**

# Super FAP-E<sup>3S</sup> series

### N-CHANNEL SILICON POWER MOSFET

#### Features

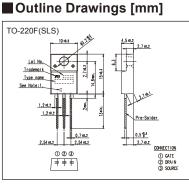
Maintains both low power loss and low noise Lower R<sub>DS</sub>(on) characteristic More controllable switching dv/dt by gate resistance Smaller V<sub>GS</sub> ringing waveform during switching Narrow band of the gate threshold voltage (4.2±0.5V) High avalanche durability

#### Applications

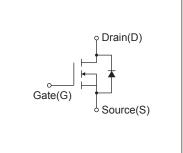
Switching regulators UPS (Uninterruptible Power Supply) **DC-DC converters** 

#### Maximum Ratings and Characteristics

#### • Absolute Maximum Ratings at Tc=25°C (unless otherwise specified)



Equivalent circuit schematic



Description	Symbol	Characteristics	Unit	Remarks
Durain Oranna Maltana	VDS	600	V	
Drain-Source Voltage	VDSX	600	V	V <sub>GS</sub> = -30V
Continuous Drain Current	lo	±17	A	
Pulsed Drain Current	DP	±68	A	
Gate-Source Voltage	Vgs	±30	V	
Repetitive and Non-Repetitive Maximum AvalancheCurrent	lar	17	A	Note*1
Non-Repetitive Maximum Avalanche Energy	Eas	765.5	mJ	Note*2
Repetitive Maximum Avalanche Energy	Ear	12	mJ	Note*3
Peak Diode Recovery dV/dt	dV/dt	4.2	kV/µs	Note*4
Peak Diode Recovery -di/dt	-di/dt	100	A/µs	Note*5
Mauinum Baura Diagingéi a	D	2.16	14/	Ta=25°C
Maximum Power Dissipation	PD	120	W	Tc=25°C
On another and Otamora Tamoration and	Tch	150	°C	
Operating and Storage Temperature range	Tstg	-55 to + 150	°C	
Isolation Voltage	Viso	2	kVrms	t = 60sec, f = 60Hz

#### • Electrical Characteristics at Tc=25°C (unless otherwise specified)

Description	Symbol	Conditions		min.	typ.	max.	Unit	
Drain-Source Breakdown Voltage	BVDSS	ID=250µA, VGS=0V	I <sub>D</sub> =250µA, V <sub>GS</sub> =0V		-	-	V	
Gate Threshold Voltage	Vgs (th)	ID=250µA, VDS=VGS	ID=250µA, VDS=VGS		4.2	4.7	V	
Zana Oata Valtana Dusin Ourrant		V <sub>DS</sub> =600V, V <sub>GS</sub> =0V	Tch=25°C	-	-	25		
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> =480V, V <sub>GS</sub> =0V	Tch=125°C	-	-	250	- μΑ	
Gate-Source Leakage Current	Igss	V <sub>GS</sub> =±30V, V <sub>DS</sub> =0V		-	10	100	nA	
Drain-Source On-State Resistance	RDS (ON)	I <sub>D</sub> =8.5A, V <sub>GS</sub> =10V		-	0.34	0.40	Ω	
Forward Transconductance	<b>g</b> fs	ID=8.5A, VDS=25V	ID=8.5A, VDS=25V		11	-	S	
Input Capacitance	Ciss	Vps=25V Vgs=0V f=1MHz		-	2500	3750	pF	
Output Capacitance	Coss			-	280	420		
Reverse Transfer Capacitance	Crss			-	16	24		
Turn-On Time	td(on)	V <sub>cc</sub> =300V V <sub>cs</sub> =10V I <sub>D</sub> =8.5A R <sub>c</sub> =15Ω		-	46	69	ns	
	tr			-	41	61.5		
Turn-Off Time	td(off)			-	110	165		
	tf			-	20	30		
Total Gate Charge	QG	V <sub>cc</sub> =300V I <sub>D</sub> =17A V <sub>GS</sub> =10V		-	68	114	nC	
Gate-Source Charge	QGS			-	23	34.5		
Gate-Drain Charge	QGD			-	24	36		
Gate-Drain Crossover Charge	Qsw			-	10	15		
Avalanche Capability	lav	L=2.00mH, T <sub>ch</sub> =25°C		17	-	-	A	
Diode Forward On-Voltage	Vsd	IF=17A, VGS=0V, Tch=25°C		-	0.90	1.35	V	
Reverse Recovery Time	trr	IF=17A, VGS=0V		-	0.75	-	μS	
Reverse Recovery Charge	Qrr	-di/dt=100A/µs, Tch=25°C		-	10	-	μC	

#### Thermal Characteristics

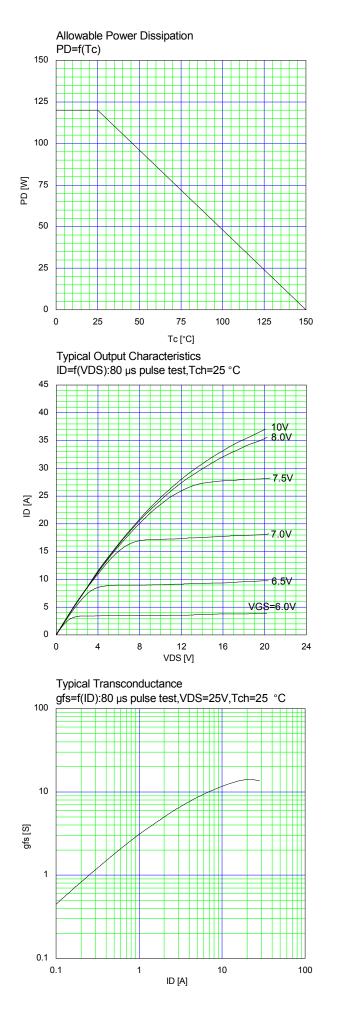
Description	Symbol	Test Conditions	min.	typ.	max.	Unit
Thermal resistance	Rth (ch-c)	Channel to case			1.040	°C/W
	Rth (ch-a)	Channel to ambient			58.0	°C/W

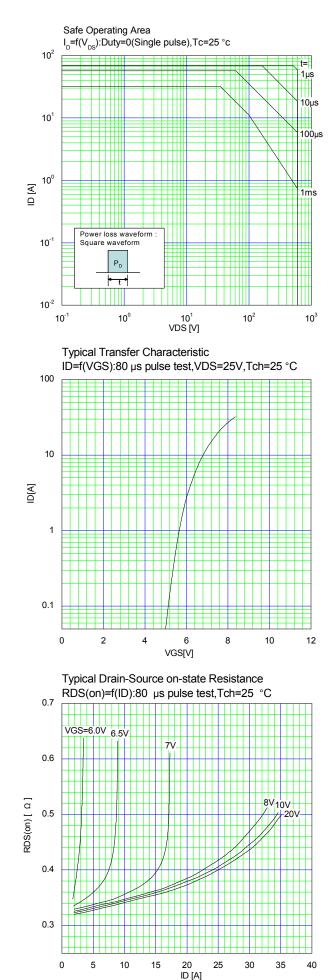
Note \*1 : Tch≤150°C

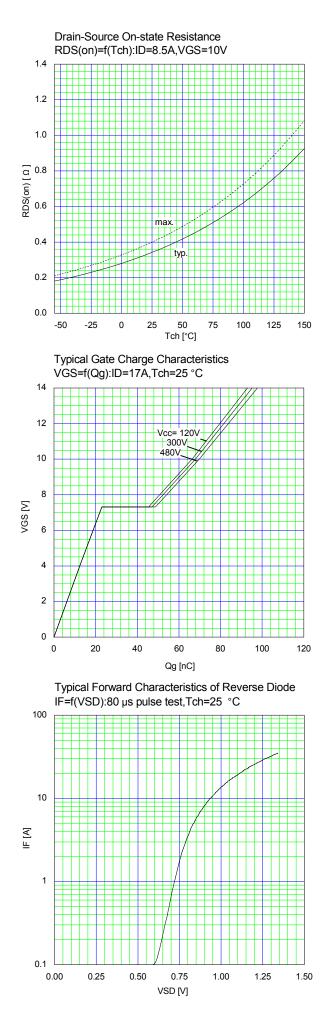
Note 1 : Italia 50 °C, IAs=7A, L=28.6mH, Vcc=60V, RG=50Ω EAs limited by maximum channel temperature and avalanche current. See to 'Avalanche Energy' graph.

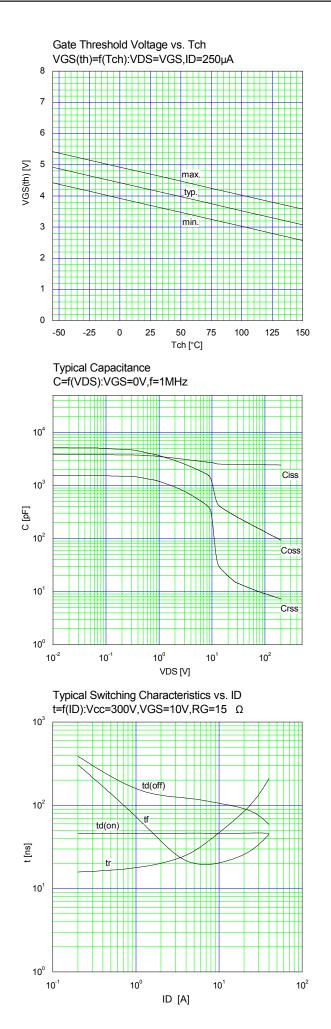
Note \*3 : Repetitive rating : Pulse width limited by maximum channel temperature.

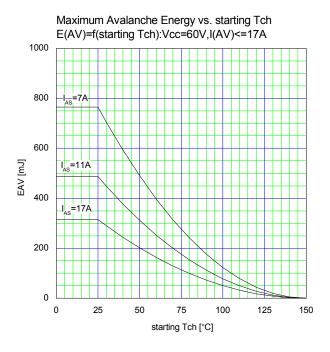
See to the 'Transient Themal impeadance' graph. Note \*4 :  $I_F \le I_D$ ,  $-di/dt = 100A/\mu_S$ ,  $Vcc \le BV_{DSS}$ ,  $Tch \le 150^\circ C$ . Note \*5 :  $I_F \le I_D$ ,  $dv/dt = 4.2kV/\mu_S$ ,  $Vcc \le BV_{DSS}$ ,  $Tch \le 150^\circ C$ .



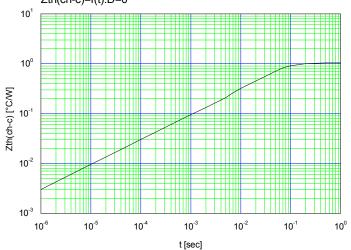








Maximum Transient Thermal Impedance Zth(ch-c)=f(t):D=0



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		WARNING		
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<ul> <li>Machine tools</li> </ul>	<ul> <li>Audiovisual equipment</li> </ul>	<ul> <li>Electrical home appliances</li> </ul>	<ul> <li>Personal equipment</li> </ul>	<ul> <li>Industrial robots etc.</li> </ul>
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